


<b>Search Notes</b> 	<b>Application No.</b>	<b>Applicant(s)</b>	
	09/817,225	AZUMA, NOBUHIRO	
	<b>Examiner</b>	<b>Art Unit</b>	
	Tan Dean D. Nguyen	3629	

SEARCHED			
Class	Subclass	Date	Examiner
705	1	5/05	DM
	14	8/05	
	17		
	16		
	26		
	27		
	39		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
	1/05	
I US	8/05	DM
1. US Patent		
2. PG Pub		
II Foreign		
1. epo		
2. JPO		
3. Derwent		